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APPLICANTS

Tadashi Mitsui, Kanagawa, JAPAN;

gp

** CONTINUING DATA *****

gp

** FOREIGN APPLICATIONS *****

JAPAN 2002-281572 09/26/2002

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Verified and <u>Allowance</u> Acknowledged <u>05/0</u>	STATE OR COUNTRY JAPAN	SHEETS DRAWING 14	TOTAL CLAIMS 30	INDEPENDENT CLAIMS 12
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ADDRESS

22852
 FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER
 LLP
 901 NEW YORK AVENUE, NW
 WASHINGTON , DC
 20001-4413

TITLE

Pattern measurement method, manufacturing method of semiconductor device, pattern measurement apparatus, and program

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